

Substitute for Form 1449 A & B/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet

1

of

2

Complete if Known

Application Number	09/851,779
Confirmation Number	4385
Filing Date	May 08, 2001
First Named Inventor	Boaz KENAN
Art Unit	2623
Examiner Name	J. MANCUSO V. BALI
Attorney Docket Number	CA1130

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
VB		US 6,016,357		01-18-2000	Neary et al.
VB		US 6,072,898		06-06-2000	Beaty et al.
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Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
VB		BUDD, RUSSELL A., et al., "A New Tool for Phase Shift Mask Evaluation, the Stepper Equivalent Aerial Image Measurement System - AIMS™," SPIE, Vol. 2087 Photomask Technology and Management (1993).	
VB		SCHENKER, RICHARD, "Comparison of Single and Dual Exposure Phase Shift Mask Approaches for Poly Gate Patterning," SPIE, Vol. 3546, September 1998.	
VB		LEVENSON, MARC D., et al., "Improving Resolution in Photolithography with a Phase Shifting Mask," IEEE Transactions on Electron Devices, Vol. ED-29, No. 12, December 1982.	
VB		BUDD, R.A., et al., "A New Mask Evaluation Tool, the Microlithography Simulation Microscope Aerial Image Measurement System," Optical/Laser Microlithography 7, San Jose, March 2-4, 1994, Proceedings of SPIE, Optical/Laser Microlithography, Bellingham, SPIE, US Vol. 2197, pages 530-540.	

Examiner Signature

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Substitute for Form 1449 A & B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		O I P E OCT 06 2005 P A T E N T O F F I C E		Complete if Known	
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Sheet	2	of	2		

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Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
VB		US 6,327,033		12-04-2001	Ferguson et al.
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